IN THE CLAIMS

Please amend the claims as follows:

Claim 1 (Currently Amended): A method of manufacturing inspecting an optical device, comprising:

placing an inspection gauge on a main surface of said optical device, said inspection gauge being provided with a density pattern formed on a transparent sheet or film; and comparing optical unevenness of said optical device with said density pattern of said inspection gauge in light of a density degree to determine whether said optical unevenness is lighter or darker in density than or equal to said density pattern of said inspection gauge.

Claim 2 (Currently Amended): A method of manufacturing an optical device The method according to Claim 1, wherein said optical device projects light from said main surface when said optical device is enabled.

Claim 3 (Currently Amended): A method of manufacturing an optical device The method according to Claim 1, wherein said inspection gauge is placed on said main surface of said optical device in order for said density pattern to be next to said optical unevenness.

Claim 4 (Currently Amended): A method of manufacturing an optical device The method according to Claim 1, wherein said inspection gauge is placed on said main surface of said optical device in order for said density pattern to cover said optical unevenness.

Claim 5 (Currently Amended): A method of manufacturing an optical device The method according to Claim 1, wherein said inspection gauge includes a plurality of different degree of density patterns.

Claim 6 (Currently Amended): A method of manufacturing an optical device The method according to Claim 5, wherein said different degree of density patterns are disposed in order of density degrees.

Claim 7 (Currently Amended): A method of manufacturing an optical device The method according to Claim 6, wherein said different degree of density patterns are applied in said order of density degrees to said optical unevenness for comparison with said optical unevenness or for inspection as to whether a difference between said different degree of density patterns and said optical unevenness is visible or not.

Claim 8 (Currently Amended): A method of manufacturing an optical device The method according to Claim 1, wherein at least one of said density patterns is made of dots provided on said sheet or film and said density degree is expressed by a rate of dots occupied per unit area.

Claim 9 (Currently Amended): A method of manufacturing an optical device The method according to Claim 8, wherein said dots are discrete circles or rectangles which are uniformly dispersed.

Claim 10 (Currently Amended): A method of manufacturing an optical device The method according to Claim 8, wherein said dots are of a predetermined size.

Claim 11 (Currently Amended): A method of manufacturing an optical device The method according to Claim 8, wherein said dots are less than or equal to 40 μ m in size.

Claim 12 (Currently Amended): A method of manufacturing an optical device The method according to Claim 8, wherein said inspection gauge includes density patterns with different dot occupied rates and said dot occupied rates range from 3% through 45%.

Claim 13 (Currently Amended): A method of manufacturing an optical device The method according to Claim 12, wherein said density patterns of said inspection gauge include low density levels each defined by a discretely additional and predetermined dot occupied rate ranging from 1% to 3% and high density levels each defined by a discrete additional dot occupied rate of 5%.

Claim 14 (Currently Amended): A method of manufacturing an optical device The method according to Claim 1, wherein said optical device is a display panel.

Claim 15 (Currently Amended): A method of manufacturing an optical device The method according to Claim 1, wherein said optical device is an illumination apparatus.

Claim 16 (Original): An inspection gauge to assess optical unevenness on a main surface of an optical device, comprising:

a transparent base sheet or film; and

a density pattern provided on said base sheet or film,

wherein said density pattern is made of a set of dots which are less than or equal to 40 μm in size.